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SJ

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SJ/T 10805-2018

Replacing SJ/T 10805-2000

**Semiconductor integrated circuits Measuring methods for
voltage comparators**

半导体集成电路 电压比较器测试方法
(English Translation)

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What this standard covers

This standard specifies the electrical characteristics test method for semiconductor integrated circuit voltage comparators (hereinafter referred to as devices). This standard is applicable to the geometric measurement of through-silicon via size. The through-silicon via can penetrate through the silicon wafer or partially through the silicon wafer. The through-silicon via can contain metal conductors and other media, or it can contain metal conductors and others. medium.

Document data

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Standards quoted by this document

SJ/T 10734-1996